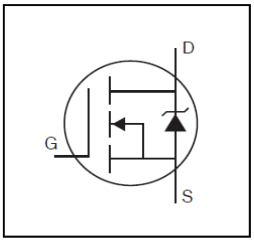
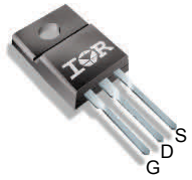
HEXFET® Power MOSFET

**Applications**
- High Efficiency Synchronous Rectification in SMPS
- Uninterruptible Power Supply
- High Speed Power Switching
- Hard Switched and High Frequency Circuits




| | |
|---|---|
| $V_{DSS}$ | 60V |
| $R_{DS(on)}$ typ. | 2.7mΩ |
| $R_{DS(on)}$ max. | 3.4mΩ |
| $I_D$ | 86A |

**Benefits**
- Improved Gate, Avalanche and Dynamic dV/dt Ruggedness
- Fully Characterized Capacitance and Avalanche SOA
- Enhanced body diode dV/dt and dI/dt Capability
- Lead-Free




TO-220 Full-Pak

| G | D | S |
|---|---|---|
| Gate | Drain | Source |

| Base Part Number | Package Type | Standard Pack | | Orderable Part Number |
|---|---|---|---|---|
| | | Form | Quantity | |
| IRFI7536GPbF | TO-220 Full-Pak | Tube | 50 | IRFI7536GPbF |

**Absolute Maximum Ratings**

| Symbol | Parameter | Max. | Units |
|---|---|---|---|
| $I_D$ @ $T_C$ = 25°C | Continuous Drain Current, $V_{GS}$ @ 10V | 86 | A |
| $I_D$ @ $T_C$ = 100°C | Continuous Drain Current, $V_{GS}$ @ 10V | 73 | |
| $I_{DM}$ | Pulsed Drain Current ① | 820 | |
| $P_D$ @$T_C$ = 25°C | Maximum Power Dissipation | 75 | W |
| | Linear Derating Factor | 0.5 | W/°C |
| $V_{GS}$ | Gate-to-Source Voltage | ± 20 | V |
| $T_J$<br>$T_{STG}$ | Operating Junction and<br>Storage Temperature Range | -55 to + 175 | °C |
| | Soldering Temperature, for 10 seconds (1.6mm from case) | 300 | |
| | Mounting torque, 6-32 or M3 screw | 10 lbf•in (1.1N•m) | |

**Avalanche Characteristics**

| | | | |
|---|---|---|---|
| $E_{AS}$ | Single Pulse Avalanche Energy (Thermally Limited) ② | 738 | mJ |
| $I_{AR}$ | Avalanche Current ① | See Fig. 14, 15, 22a, 22b | A |
| $E_{AR}$ | Repetitive Avalanche Energy ① | | mJ |

**Thermal Resistance**

| Symbol | Parameter | Typ. | Max. | Units |
|---|---|---|---|---|
| $R_{\theta JC}$ | Junction-to-Case ⑦⑧ | — | 2.87 | °C/W |
| $R_{\theta JA}$ | Junction-to-Ambient (PCB Mount) | — | 65 | |

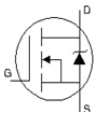
**Electrical Characteristics @ $T_J$ = 25°C (unless otherwise specified)**

| | Parameter | Min. | Typ. | Max. | Units | Conditions |
|---|---|---|---|---|---|---|
| $V_{(BR)DSS}$ | Drain-to-Source Breakdown Voltage | 60 | — | — | V | $V_{GS}$ = 0V, $I_D$ = 250µA |
| $\Delta V_{(BR)DSS}/\Delta T_J$ | Breakdown Voltage Temp. Coefficient | — | 29 | — | mV/°C | Reference to 25°C, $I_D$ = 1mA ① |
| $R_{DS(on)}$ | Static Drain-to-Source On-Resistance | — | 2.7 | 3.4 | mΩ | $V_{GS}$ = 10V, $I_D$ = 75A |
| $V_{GS(th)}$ | Gate Threshold Voltage | 2.0 | — | 4.0 | V | $V_{DS}$ = $V_{GS}$, $I_D$ = 150µA |
| gfs | Forward Trans conductance | 88 | — | — | S | $V_{DS}$ = 25V, $I_D$ = 75A |
| $R_G$ | Internal Gate Resistance | — | 0.79 | — | Ω | |
| $I_{DSS}$ | Drain-to-Source Leakage Current | — | — | 20 | µA | $V_{DS}$ = 60 V, $V_{GS}$ = 0V |
| | | — | — | 250 | | $V_{DS}$ = 60V,$V_{GS}$ = 0V,$T_J$ =125°C |
| $I_{GSS}$ | Gate-to-Source Forward Leakage | — | — | 100 | nA | $V_{GS}$ = 20V |
| | Gate-to-Source Reverse Leakage | — | — | -100 | | $V_{GS}$ = -20V |

**Dynamic @ $T_J$ = 25°C (unless otherwise specified)**

| | | | | | | |
|---|---|---|---|---|---|---|
| $Q_g$ | Total Gate Charge | — | 130 | 195 | nC | $I_D$ = 75A |
| $Q_{gs}$ | Gate-to-Source Charge | — | 31 | — | | $V_{DS}$ = 30V |
| $Q_{gd}$ | Gate-to-Drain Charge | — | 42 | — | | $V_{GS}$ = 10V ④ |
| $Q_{sync}$ | Total Gate Charge Sync. (Qg - Qgd) | — | 88 | — | | |
| $t_{d(on)}$ | Turn-On Delay Time | — | 22 | — | ns | $V_{DD}$ = 39V |
| $t_r$ | Rise Time | — | 77 | — | | $I_D$ = 75A |
| $t_{d(off)}$ | Turn-Off Delay Time | — | 55 | — | | $R_G$= 2.7Ω |
| $t_f$ | Fall Time | — | 64 | — | | $V_{GS}$ = 10V ④ |
| $C_{iss}$ | Input Capacitance | — | 6600 | — | pF | $V_{GS}$ = 0V |
| $C_{oss}$ | Output Capacitance | — | 720 | — | | $V_{DS}$ = 48V |
| $C_{rss}$ | Reverse Transfer Capacitance | — | 400 | — | | $f$ = 1.0MHz, See Fig. 5 |
| $C_{oss\ eff.\ (ER)}$ | Effective Output Capacitance (Energy Related) | — | 1080 | — | | $V_{GS}$=0V,$V_{DS}$= 0V to 48V See Fig.11⑥ |
| $C_{oss\ eff.\ (TR)}$ | Effective Output Capacitance (Time Related) | — | 1400 | — | | $V_{GS}$ = 0V, $V_{DS}$ = 0V to 48V ⑤ |

**Source-Drain Ratings and Characteristics**

| | Parameter | Min. | Typ. | Max. | Units | Conditions |
|---|---|---|---|---|---|---|
| $I_S$ | Continuous Source Current (Body Diode) | — | — | 86 | A | MOSFET symbol showing the integral reverse p-n junction diode.  |
| $I_{SM}$ | Pulsed Source Current (Body Diode) ① | — | — | 820 | | |
| $V_{SD}$ | Diode Forward Voltage | — | — | 1.3 | V | $T_J$ = 25°C,$I_S$ = 75A,$V_{GS}$ = 0V ④ |
| dv/dt | Peak Diode Recovery dv/dt | — | 3.3 | — | V/ns | $T_J$ = 25°C, $I_S$ = 75A, $V_{DS}$ = 60V |
| $t_{rr}$ | Reverse Recovery Time | — | 43 | — | ns | $T_J$ = 25°C, $V_R$ = 51V |
| | | | 53 | — | | $T_J$ = 125°C, $I_F$=75A |
| $Q_{rr}$ | Reverse Recovery Charge | — | 58 | — | nC | $T_J$ = 25°C, di/dt= 100A/µs④ |
| | | — | 65 | — | | $T_J$ = 125°C |
| $I_{RRM}$ | Reverse Recovery Current | — | 2.4 | — | A | $T_J$ = 25°C |

**Notes:**

① Repetitive rating; pulse width limited by max. junction temperature. (See fig. 11)

② Limited by $T_{Jmax}$, starting $T_J$ = 25°C, L = 0.26mH, $R_G$ = 50Ω, $I_{AS}$ = 75A, $V_{GS}$ =10V. Part not recommended for use above this value.

③ $I_{SD}$ ≤ 75A, di/dt ≤ 890A/µs, $V_{DD}$ ≤ $V_{(BR)DSS}$, $T_J$ ≤ 175°C.

④ Pulse width ≤ 400µs; duty cycle ≤ 2%.

⑤ $C_{oss\ eff.}$ (TR) is a fixed capacitance that gives the same charging time as $C_{oss}$ while $V_{DS}$ is rising from 0 to 80% $V_{DSS}$.

⑥ $C_{oss\ eff.}$ (ER) is a fixed capacitance that gives the same energy as $C_{oss}$ while $V_{DS}$ is rising from 0 to 80% $V_{DSS}$.

⑦ $R_\theta$ is measured at $T_J$ approximately 90°C.

⑦ $R_{\theta JC}$ value shown is at time zero.

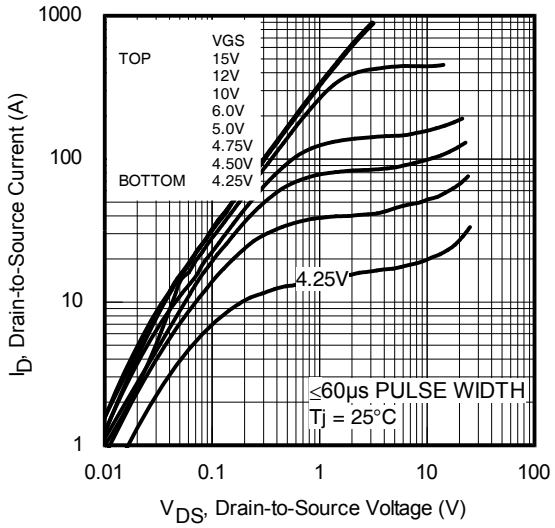



**Fig. 1** Typical Output Characteristics

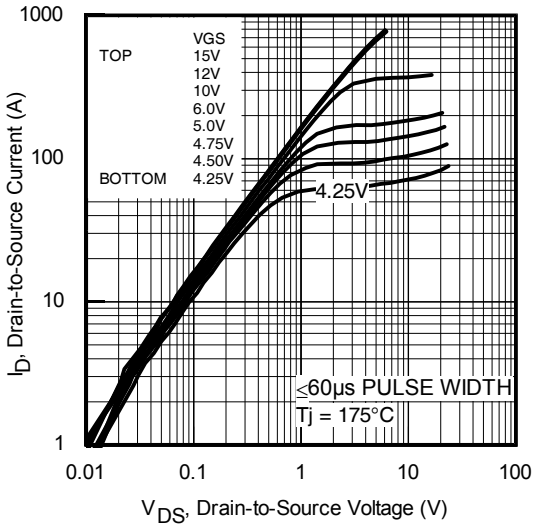



**Fig. 2** Typical Output Characteristics

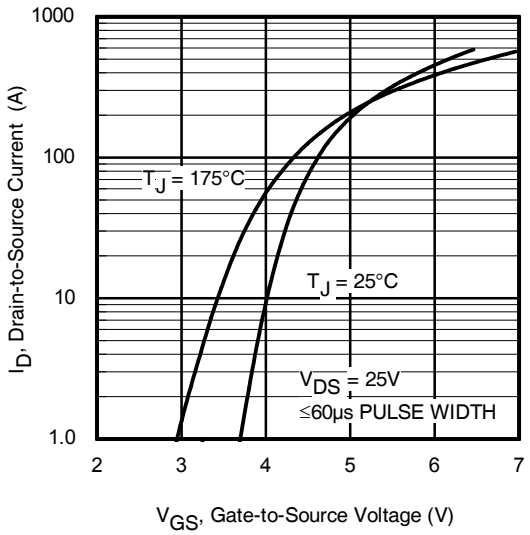



**Fig. 3** Typical Transfer Characteristics

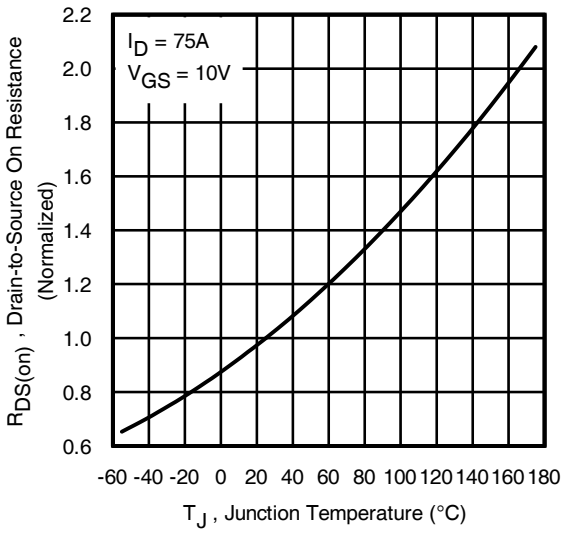



**Fig. 4** Normalized On-Resistance vs. Temperature

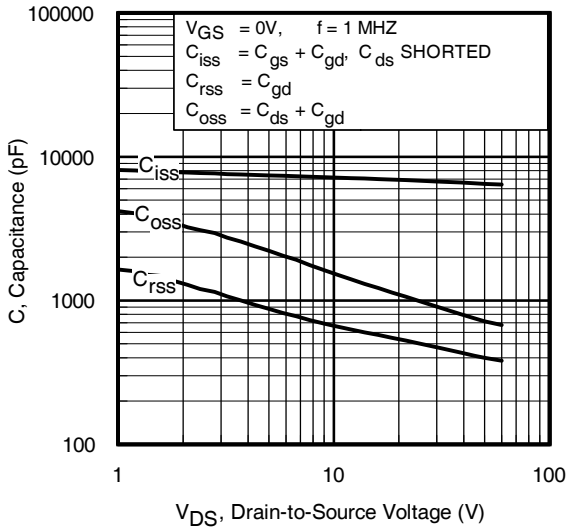



**Fig 5.** Typical Capacitance vs. Drain-to-Source Voltage

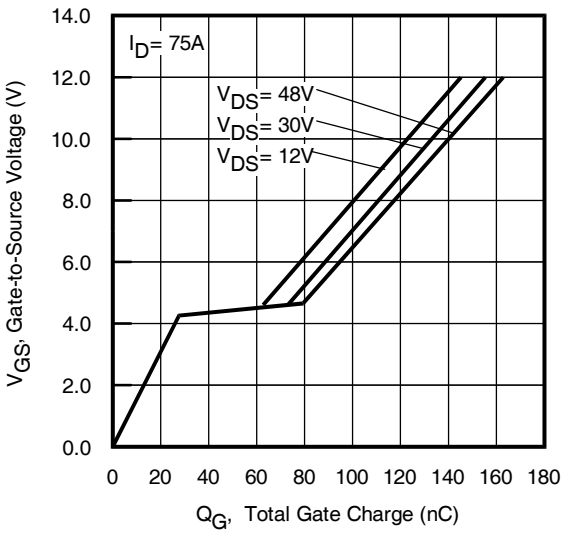



**Fig 6.** Typical Gate Charge vs. Gate-to-Source Voltage

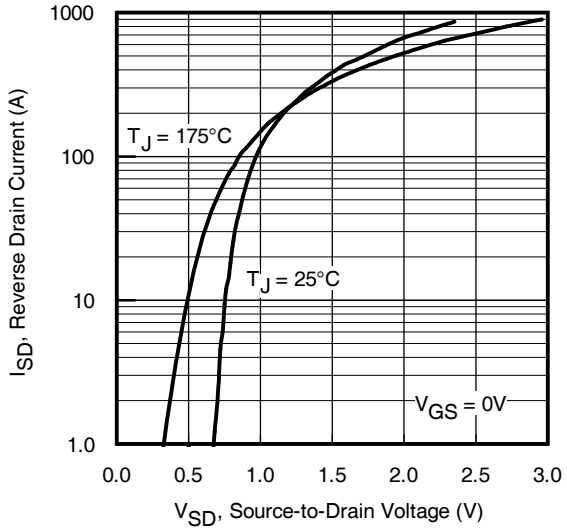



**Fig. 7.** Typical Source-to-Drain Diode Forward Voltage

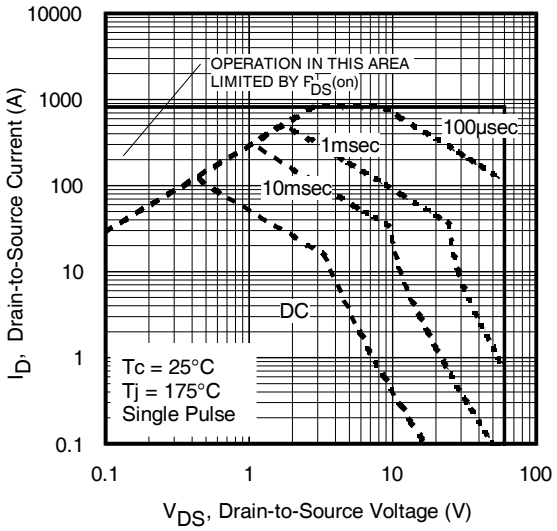



**Fig 8.** Maximum Safe Operating Area

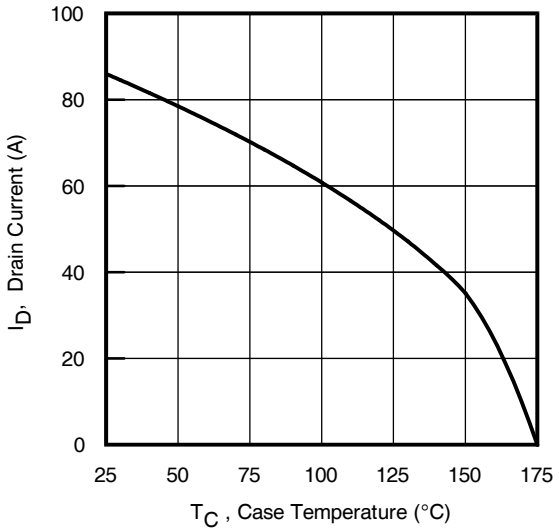



**Fig. 9.** Maximum Drain Current vs. Case Temperature

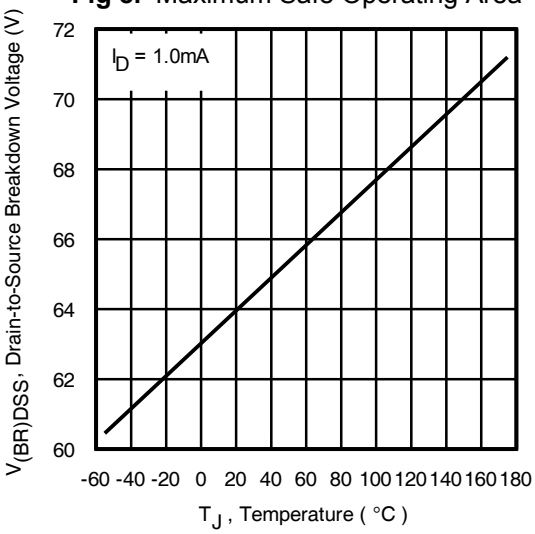



**Fig 10.** Drain-to-Source Breakdown Voltage

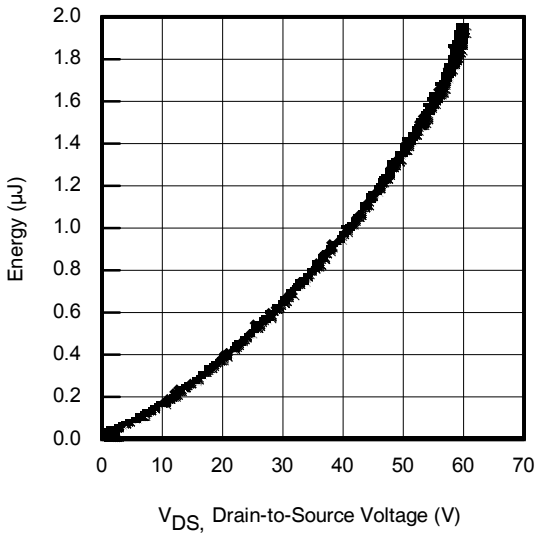



**Fig. 11.** Typical $C_{OSS}$ Stored Energy

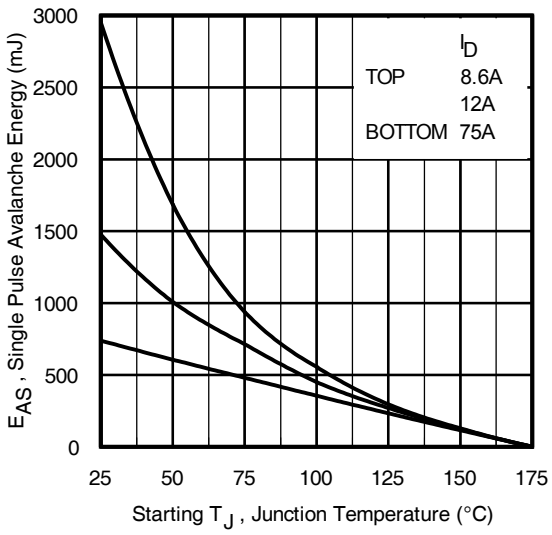



**Fig 12.** Maximum Avalanche Energy vs. Drain Current

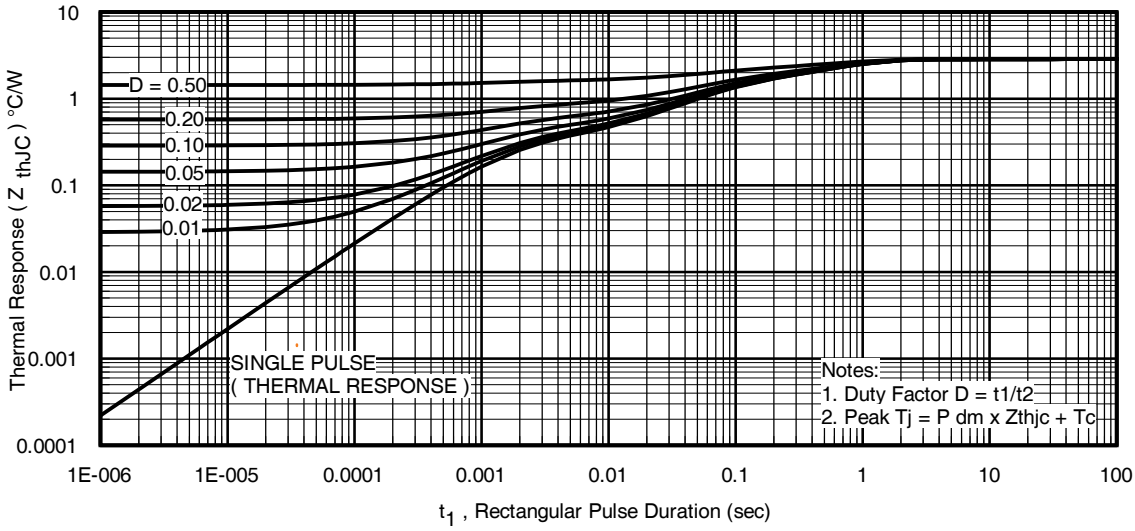



**Fig 13.** Maximum Effective Transient Thermal Impedance, Junction-to-Case

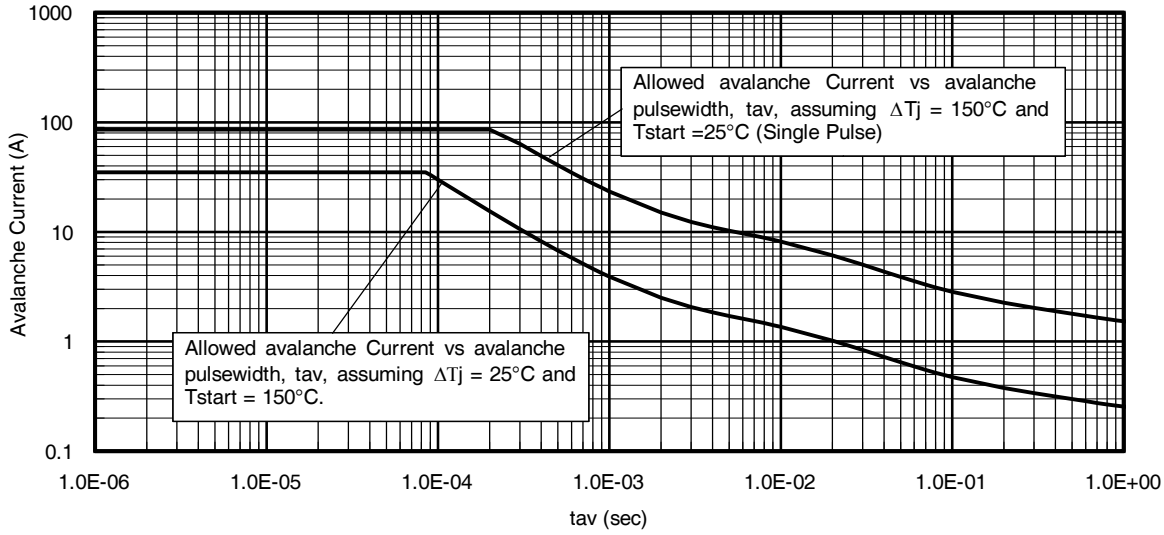
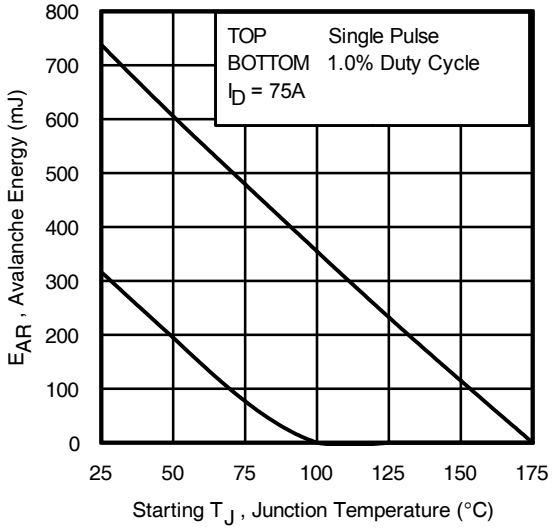



**Fig 14.** Single Avalanche Event: Pulse Current vs. Pulse Width




**Notes on Repetitive Avalanche Curves , Figures 14, 15:**
**(For further info, see AN-1005 at www.infineon.com)**

1.Avalanche failures assumption:
Purely a thermal phenomenon and failure occurs at a temperature far in excess of $T_{jmax}$. This is validated for every part type.
2. Safe operation in Avalanche is allowed as long as$T_{jmax}$ is not exceeded.
3. Equation below based on circuit and waveforms shown in Figures 16a, 16b.
4. $P_{D\ (ave)}$ = Average power dissipation per single avalanche pulse.
5. BV = Rated breakdown voltage (1.3 factor accounts for voltage increase during avalanche).
6. $I_{av}$ = Allowable avalanche current.
7. $\Delta T$ = Allowable rise in junction temperature, not to exceed $T_{jmax}$ (assumed as 25°C in Figure 14, 15).
$t_{av}$ = Average time in avalanche.
D = Duty cycle in avalanche = tav ·f
$Z_{thJC}(D, t_{av})$ = Transient thermal resistance, see Figures 13)

$$P_{D\ (ave)} = 1/2\ (1.3 \cdot BV \cdot I_{av}) = \Delta T / Z_{thJC}$$
$$I_{av} = 2\Delta T / [1.3 \cdot BV \cdot Z_{th}]$$
$$E_{AS\ (AR)} = P_{D\ (ave)} \cdot t_{av}$$

**Fig 15.** Maximum Avalanche Energy vs. Temperature

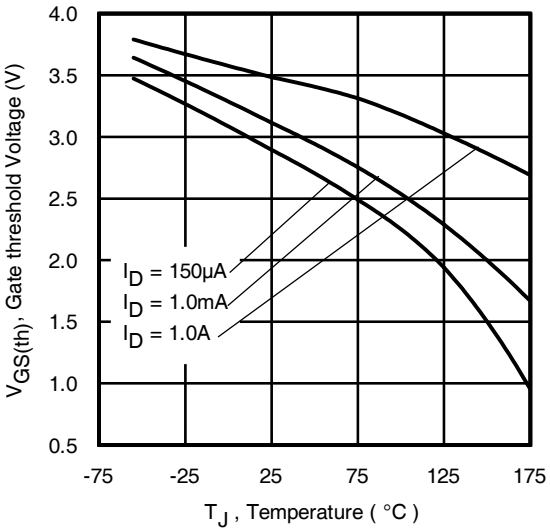



**Fig 16.** Threshold Voltage vs. Temperature

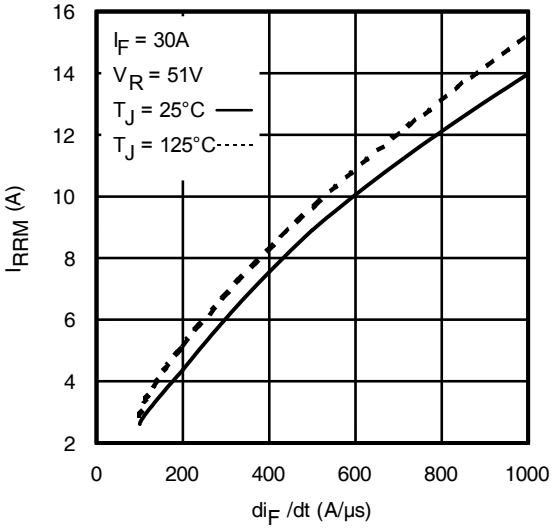



**Fig 17.** Typical Recovery Current vs. dif/dt

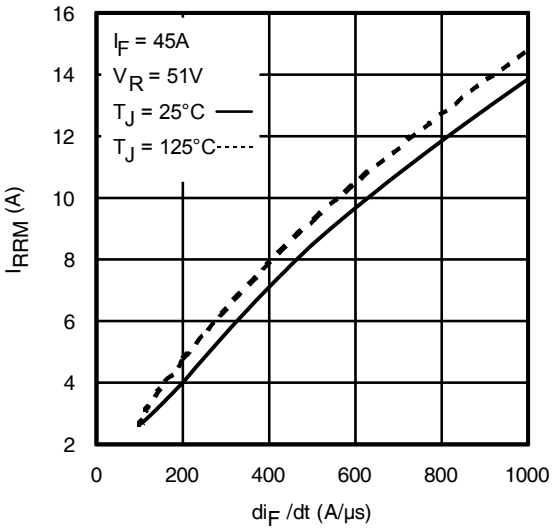



**Fig 18.** Typical Recovery Current vs. dif/dt

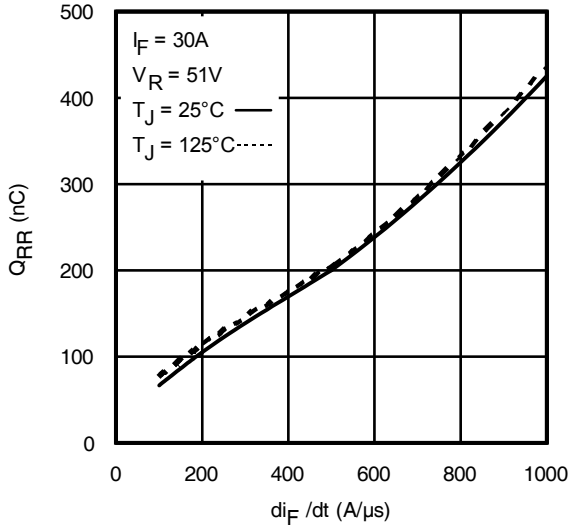



**Fig 19.** Typical Stored Charge vs. dif/dt

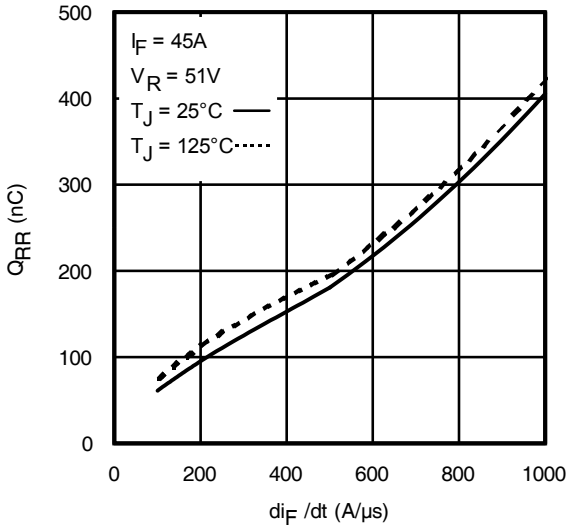



**Fig 20.** Typical Stored Charge vs. dif/dt

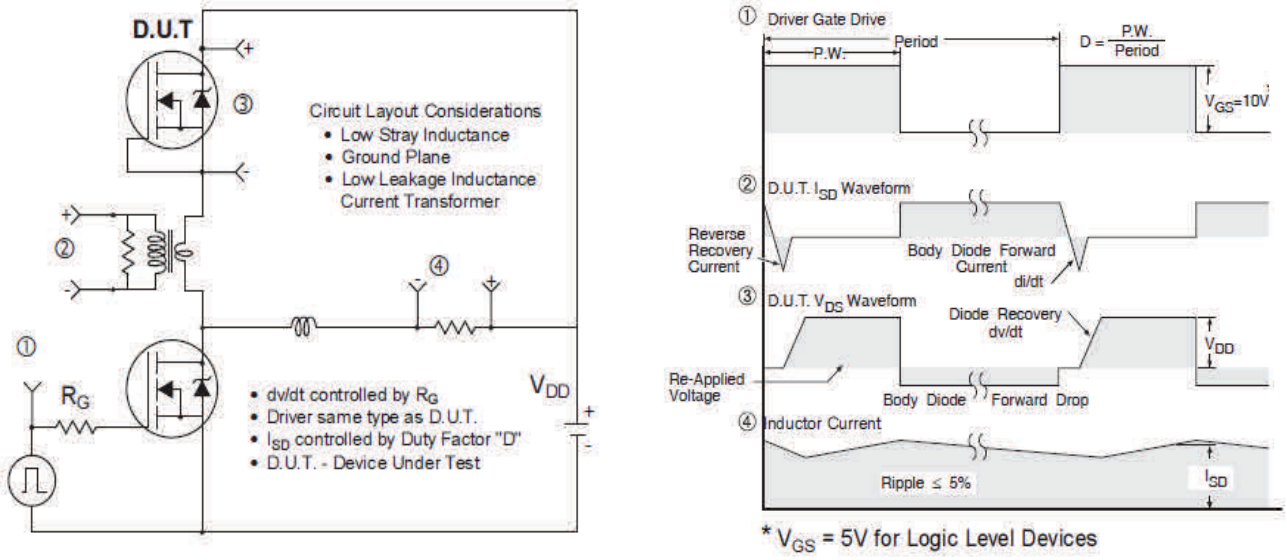



**Fig 21.** Peak Diode Recovery dv/dt Test Circuit for N-Channel HEXFET® Power MOSFETs

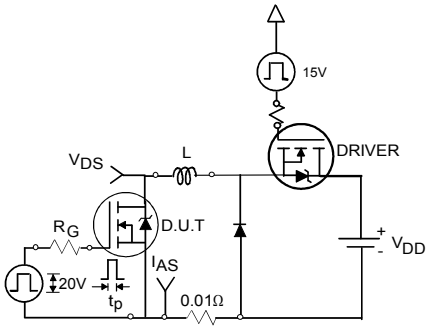



**Fig 22a.** Unclamped Inductive Test Circuit

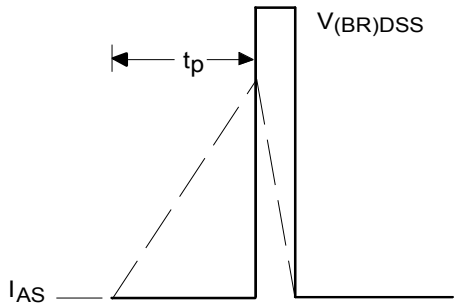



**Fig 22b.** Unclamped Inductive Waveforms

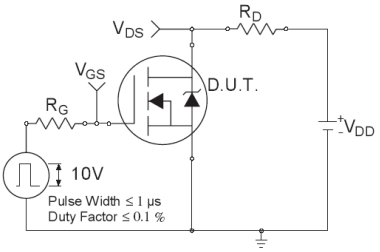



**Fig 23a.** Switching Time Test Circuit

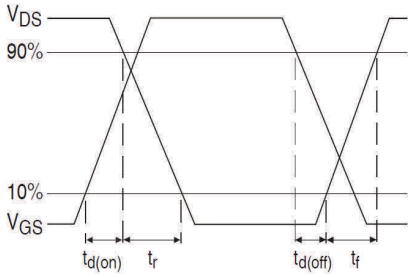



**Fig 23b.** Switching Time Waveforms

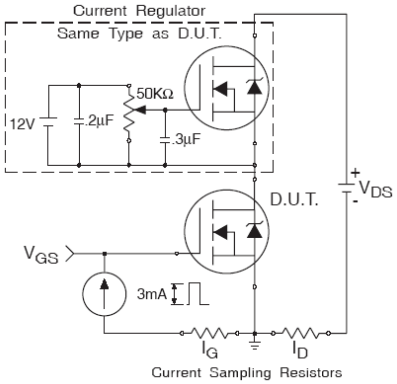



**Fig 24a.** Gate Charge Test Circuit

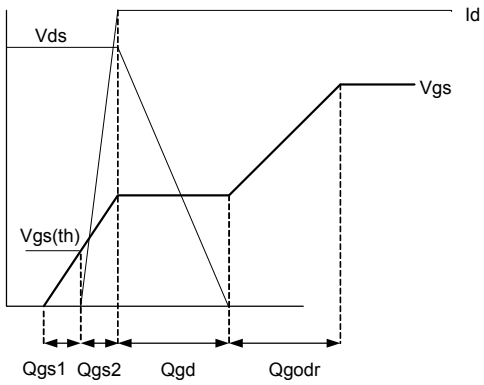
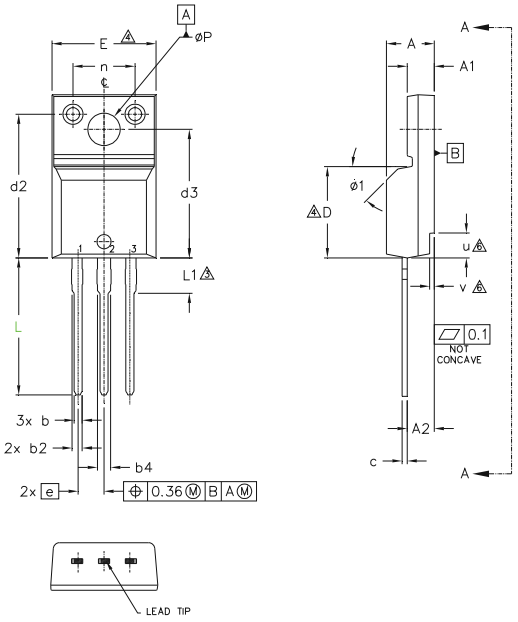
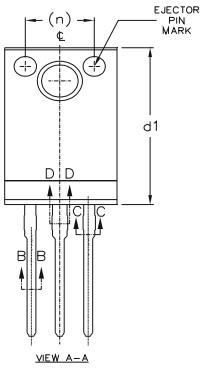
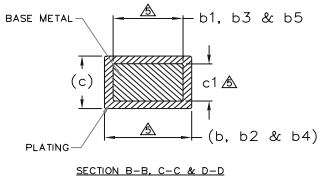



**Fig 24b.** Gate Charge Waveform

**TO-220 Full-Pak Package Outline** (Dimensions are shown in millimeters (inches))




NOTES:

1.0 DIMENSIONING AND TOLERANCING AS PER ASME Y14.5 M– 1994.

2.0 DIMENSIONS ARE SHOWN IN MILLIMETERS [INCHES].

3.0 LEAD DIMENSION AND FINISH UNCONTROLLED IN L1.

4.0 DIMENSION D & E DO NOT INCLUDE MOLD FLASH. MOLD FLASH SHALL NOT EXCEED .005" (0.127) PER SIDE. THESE DIMENSIONS ARE MEASURED AT THE OUTER MOST EXTREMES OF THE PLASTIC BODY.

5.0 DIMENSION b1, b3, b5 & c1 APPLY TO BASE METAL ONLY.

6.0 STEP OPTIONAL ON PLASTIC BODY DEFINED BY DIMENSIONS u & v.

7.0 CONTROLLING DIMENSION : INCHES.

| SYMBOL | DIMENSIONS | | | | NOTES |
|---|---|---|---|---|---|
| | MILLIMETERS | | INCHES | | |
| | MIN. | MAX. | MIN. | MAX. | |
| A | 4.57 | 4.83 | .180 | .190 | |
| A1 | 2.57 | 2.82 | .101 | .111 | |
| A2 | 2.51 | 2.92 | .099 | .115 | |
| b | 0.61 | 0.94 | .024 | .037 | |
| b1 | 0.61 | 0.89 | .024 | .035 | 5 |
| b2 | 0.76 | 1.27 | .030 | .050 | |
| b3 | 0.76 | 1.22 | .030 | .048 | 5 |
| b4 | 1.02 | 1.52 | .040 | .060 | |
| b5 | 1.02 | 1.47 | .040 | .058 | 5 |
| c | 0.33 | 0.63 | .013 | .025 | |
| c1 | 0.33 | 0.58 | .013 | .023 | 5 |
| D | 8.66 | 9.80 | .341 | .386 | 4 |
| d1 | 15.80 | 16.13 | .622 | .635 | |
| d2 | 13.97 | 14.22 | .550 | .560 | |
| d3 | 12.29 | 12.93 | .484 | .509 | |
| E | 9.63 | 10.74 | .379 | .423 | 4 |
| e | 2.54 BSC | | .100 BSC | | |
| L | 13.21 | 13.72 | .520 | .540 | |
| L1 | 3.10 | 3.68 | .122 | .145 | 3 |
| n | 6.05 | 6.60 | .238 | .260 | |
| øP | 3.05 | 3.45 | .120 | .136 | |
| u | 2.39 | 2.49 | .094 | .098 | 6 |
| v | 0.41 | 0.51 | .016 | .020 | 6 |
| ø1 | – | 45° | – | 45° | |

LEAD ASSIGNMENTS

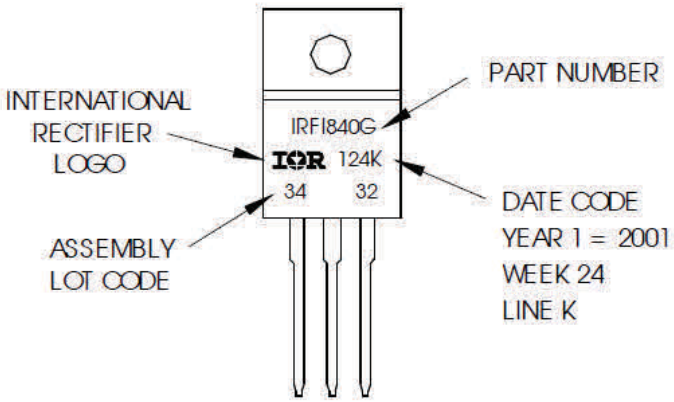
HEXFET
1.– GATE
2.– DRAIN
3.– SOURCE

IGBTs, CoPACK
1.– GATE
2.– COLLECTOR
3.– EMITTER

**TO-220 Full-Pak Part Marking Information**

EXAMPLE: THIS IS AN IRFI840G
WITH ASSEMBLY
LOT CODE 3432
ASSEMBLED ON WW 24, 2001
IN THE ASSEMBLY LINE "K"

Note: "P" in assembly line position
indicates "Lead-Free"




TO-220AB Full-Pak packages are not recommended for Surface Mount Application.

Note: For the most current drawing please refer to website at http://www.irf.com/package/

## Qualification Information

| | | |
|---|---|---|
| **Qualification Level** | Industrial (per JEDEC JESD47F) † | |
| **Moisture Sensitivity Level** | TO-220 Full-Pak | N/A |
| **RoHS Compliant** | Yes | |

† Applicable version of JEDEC standard at the time of product release.

## Revision History

| Date | Comments |
|---|---|
| 04/27/2017 | • Changed datasheet with Infineon logo - all pages.<br>• Corrected Package Outline on page 8.<br>• Corrected Qual level from “TSOP-6” to “TO-220 Full-Pak” on page 9.<br>• Added disclaimer on last page. |



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**Document reference**
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